

Rev	Description	Appd.	Date
0	initial release	lag	01-03-00

Notes:

1.0 Orientations

- 1.1 Wafer surface is normal to $\langle X \rangle \pm 0.5^\circ$
- 1.2 Flats
 - 1.2.1 Primary flat is normal to $\langle +Z \rangle \pm 0.5^\circ$.
 - 1.2.2 Secondary flat is $135^\circ \pm 1^\circ$ clockwise from the $\langle +Z \rangle$ flat when viewing the $\langle -X \rangle$ face.

2.0 Edge

- 1.1 All edges rounded with $R0.57 \pm 0.08\text{mm}$.
- 1.2 No chips more than 0.5mm in penetration and 1.0mm in length.

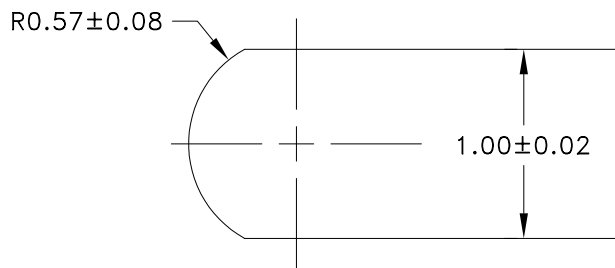
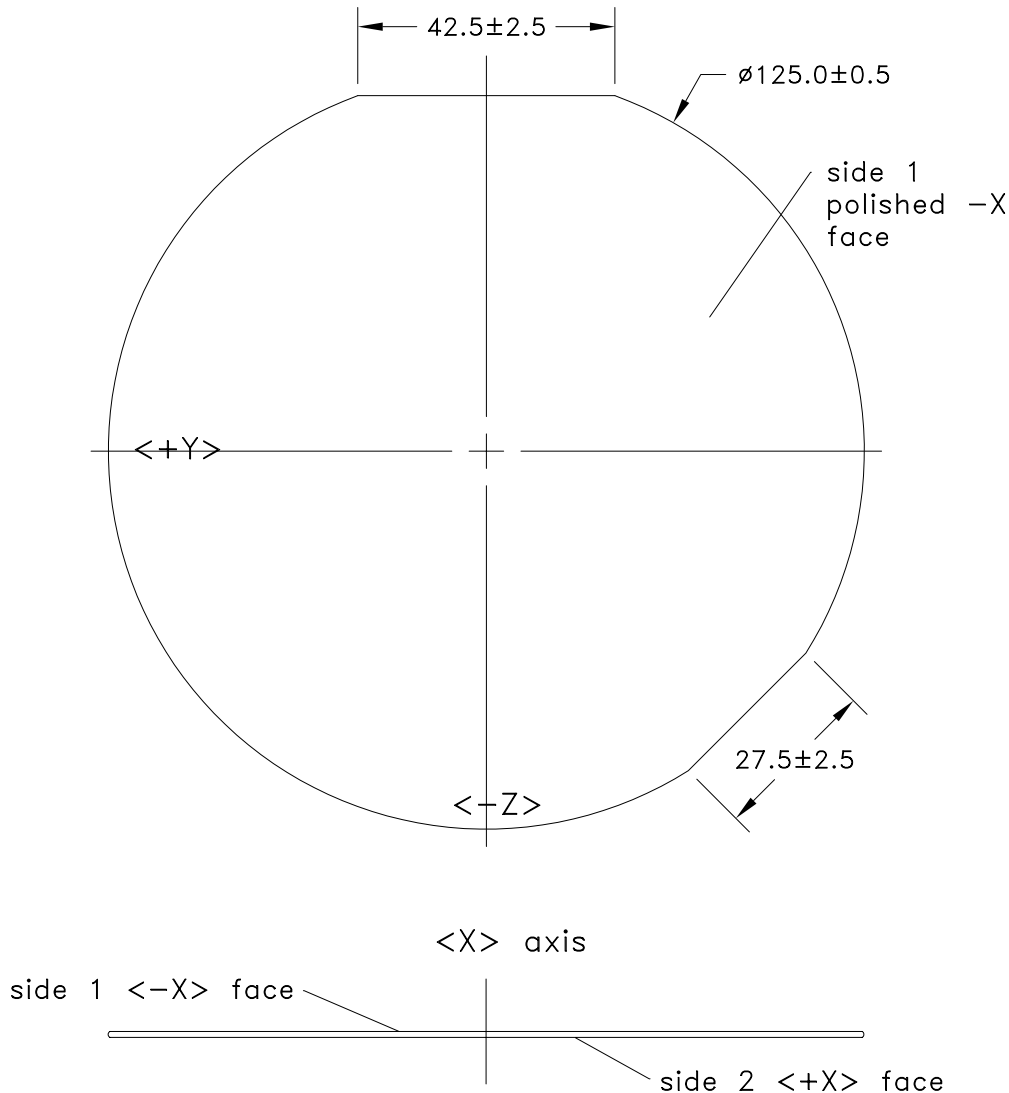
3.0 Surfaces

- 3.1 Side 1 $\langle -X \rangle$ face
Polished 10-5 scratch-dig with 1mm edge exclusion. Inspected with reflected light and unaided eye.
- 3.2 Side 2 $\langle +X \rangle$ face
Polished 60-30 scratch-dig with 1mm edge exclusion. Inspected with reflected light and unaided eye.

4.0 Flatness

- 4.1 Warp $< 50\mu\text{m}$.
- 4.2 TTV $< 25\mu\text{m}$.

For Reference Only



Wafer Edge Detail, 25X

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Material: Lithium Niobate	DR. Igordon	01-03-00	Crystal Technology, Inc. An EPCOS Company
Unless otherwise specified, dimensions in mm	CHK.		
Tolerances		APPD.	Title: LNIO 125 ϕ x 1.0mm, $\langle -X \rangle$ Po/Po, +Z FLT
Inches	Millimeters	Wafer Code:	
.X \pm 0.1	X \pm 0.5	Customer Approval:	Size: A
.XX \pm 0.01	.X \pm 0.25		Dwg. No: 97-02604-01
.XXX \pm 0.005	.XX \pm 0.1		Rev: A
.XXXX \pm 0.0020	.XXX \pm 0.05		Scale: 0.8:1
Angles \pm 0.5°	DO NOT SCALE DRAWING		Sheet 1 of 1